PHILIPS

Read-Proof Hardware from Protective Coatings

CHES 2006, Tokyo-Yokohama

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Contents

- Limitations of the Black-Box Model

- Brief Overview of Physical Attacks

- Security in a Physical World

- Methods and Requirements

- Components
  - Coating PUFs
  - Fuzzy Extractors/Helper data
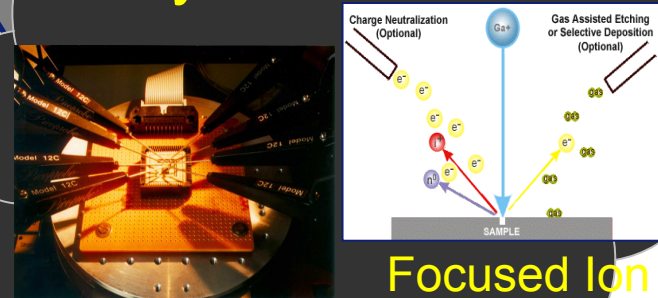
- Secure Key Storage Device

Limitations of the Black-Box Model

Mathematical Attacks Protocol Attacks

Physical Attacks

Micro Probes

Focused Ion Beam

Assumption:

IC: Black-Box

↓

Crypto guarantees
Security level
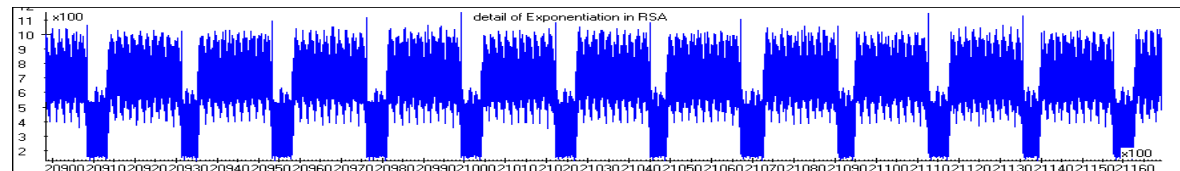
Secret Key: 001011101011

Security not guaranteed by cryptography

Brief Overview Physical Attacks

- Invasive Attacks

  - Micro Probing
  - Focused Ion Beams
  - Chemical
  - Mechanical
  - Etching

- Side Channel Attacks

  - Timing Analysis

  - Power Analysis

  - Electromagnetic Radiation

- Fault Induction (light, X-ray, power glitch)

- Optical Inspection

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5

Security in a Physical World

Big Challenge: Develop theory and practical components for security in the presence of physical leakage: **No Black-Boxes!**
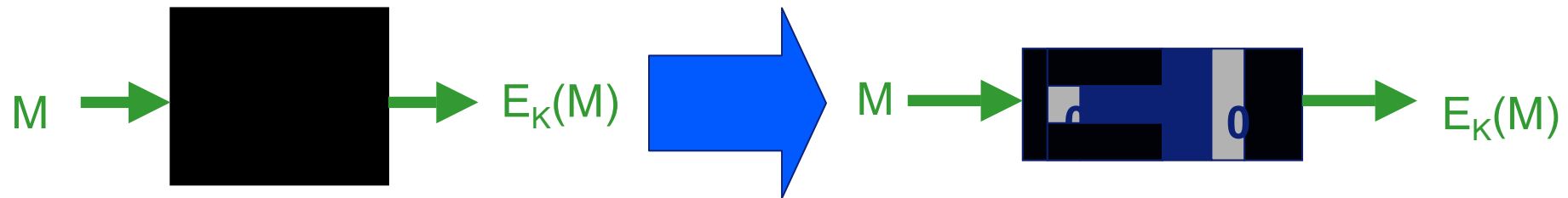
Components

1. Read-Proof Hardware:
   Enemy can not read the data stored in it

2. Tamper-Proof Hardware:
   Enemy can not change the data stored in it

3. Self Destruction Capability

Algorithmic Tamper Proof Security can be achieved [Gennaro et al]

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Goal

Practical Methods

M → ▢ → $E_K(M)$ ➡ M → ▢ → $E_K(M)$

Focus: Read-Proof Hardware

Read-Proof Hardware is hardware where the attacker can
not read any information on the data stored in it

⬇ **Practical Meaning?!**

Should be resistant against:
- Invasive Physical Attacks
- Side-Channel Attacks
- Fault Attacks
- Optical Inspection

Invasive vs Non-Invasive Attacks

Invasive Physical Attacks

Definition
An *invasive* physical attack is an attack where the attacker physically breaks into the device by modifying its structure

Examples:
- Chemical etching
- Drilling a hole
- Focused Ion Beam attack

Non - Invasive Physical Attacks

Definition
An non-*invasive* physical attack is an attack where the attacker physically breaks into the device without modifying its structure

Examples:
- Optical inspection of the memory
- Side-Channel attacks (Time, EMA, DPA, …)

Methods and Requirements

In order to protect keys against physical attacks:

1. Do **not** store a key in digital form in a device

2. Generate the key only when needed (extract it from a physical source on the IC)

3. Delete the key

Components

Two components are needed:

1. Hardware component (Physics)

1. Physical Source

2. Cryptographic component

1. Fuzzy Extractor/Helper data algorithm

Hardware Requirements

Security Requirements:

1. Physical Inscrutability (opaqueness)
2. Unclonability
    1. Physical Unclonability
    2. Mathematical Unclonability
3. Tamper evident: key is destroyed upon damage

Practicality Requirements:

1. Easy to challenge the source
2. Cheap and easy integratable on an IC
3. Excellent mechanical and chemical properties

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Components: Physical Source

Physical Unclonable Function (PUF):
Inherently unclonable Physical Structure (consisting of many random/uncontrollable components) satisfying:

- Easy to evaluate: Challenges-Responses
- Responses are unpredictable
- Inherently tamper evident
- Manufacturer not-reproducable
- Extract keys from measurements

Coating PUF

- An IC is covered with an opaque coating containing random particles with high ε_r
- Array of capacitive sensors in upper metal layer detects local coating properties.
- Inhomogeneous coating $\rightarrow$ random capacitive properties

- PUF is used as a source of secret random information which are derived from the local coating capacitances (secure key storage).
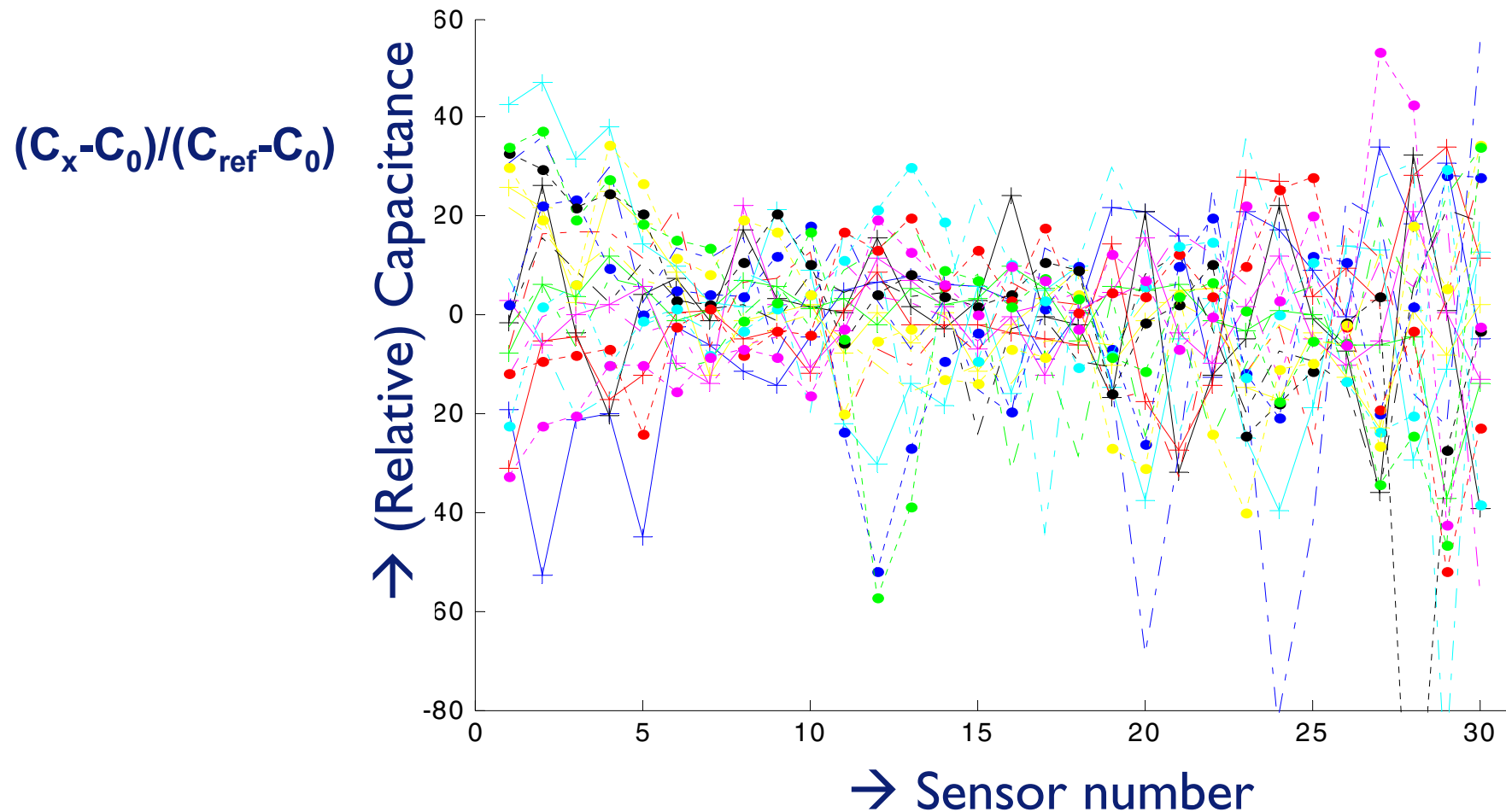
Information Content of a Coating PUF (Response)

Coating PUF [JAP06]

$$H = \log \left[\frac{\sqrt{2\pi e}}{\sigma_N} \frac{A\varepsilon_0}{d} \sqrt{\frac{q(1-q)}{Ad/s^3} \frac{|\varepsilon_1^{-1} - \varepsilon_2^{-1}|}{[(1-q)\varepsilon_1^{-1} + q\varepsilon_2^{-1}]^2}} \right]$$

$\approx$ 6.6 bits/sensor

Capacitance values of 21 ICs

$(C_x - C_0)/(C_{ref} - C_0)$

→ (Relative) Capacitance

→ Sensor number

Fuzzy Extractor/Helper Data Algorithm

- **Information present in the PUF has to be extracted**

  - Measurements (Challenges - Responses)

- **Measurements on Physical Systems are noisy**

- **Noisy values can not be used as keys in cryptography**

- **A Fuzzy Extractor/Helper Data Algorithm is needed**

Key Extraction from PUFs: Fuzzy Extractor

• Grid points represent ECC Code words

Assumption: Response X uniformly random

Enrollment

• Random codeword C(S) is chosen

• Response X is measured

• Helper data **W** is generated (difference between X and C) and stored in EEPROM

• Key **K** is generated and its public key **P(K)** is output and the Key **K** is destroyed

Key Reconstruction

• Y is noisy response

• Y+W=C'

• S'=DEC(C')

Security Condition

• $I(K;W) \leq \varepsilon$

Properties

- The parameter ε can be made negligible in the security parameter

- The maximal length of a secret key is given by

$$I(X;Y)$$

where $I(X;Y)$ is the mutual information between

Enrollment: X ⟶ Key Reconstruction: Y

Practical Key extraction requirements

- **Measured Data are continuous, not discrete!**

- **Uniformly Distributed Keys**: All possible n-bit keys must be equally probable.

- **Robustness**: key extraction must be reproducible, regardless of measurement noise.

Statistics

Uniformly Distributed Keys

- Quantization with equiprobable intervals

Achieving Robustness (I)

- Define helper-data $W*$ that shifts measurements to the center of a quantization interval.

Achieving Robustness (II)

- Assign bits to quantization intervals according to a Gray-code.

Achieving Robustness (III)

- Concatenate bits from multiple sensors to construct a key of length n.
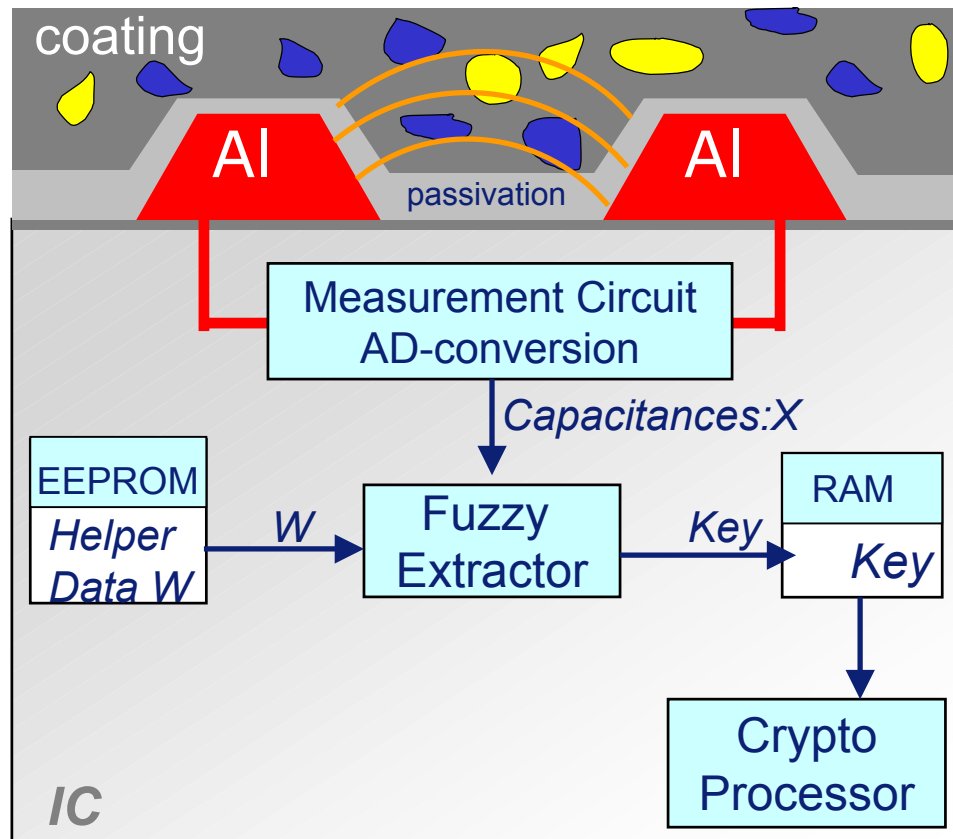- Use an Error Correcting Code (ECC) and the XOR-Fuzzy Extractor:

  Enrollment: K, $W = X \oplus C_K$

  Key Reconstruction: $Dec(Y \oplus W)$

  $\qquad\qquad\qquad = Dec(Y \oplus X \oplus C_K)$

  $\qquad\qquad\qquad = C_K$ iff $d(X,Y) < T$

Key Extraction, helperdata scheme

Enrollment
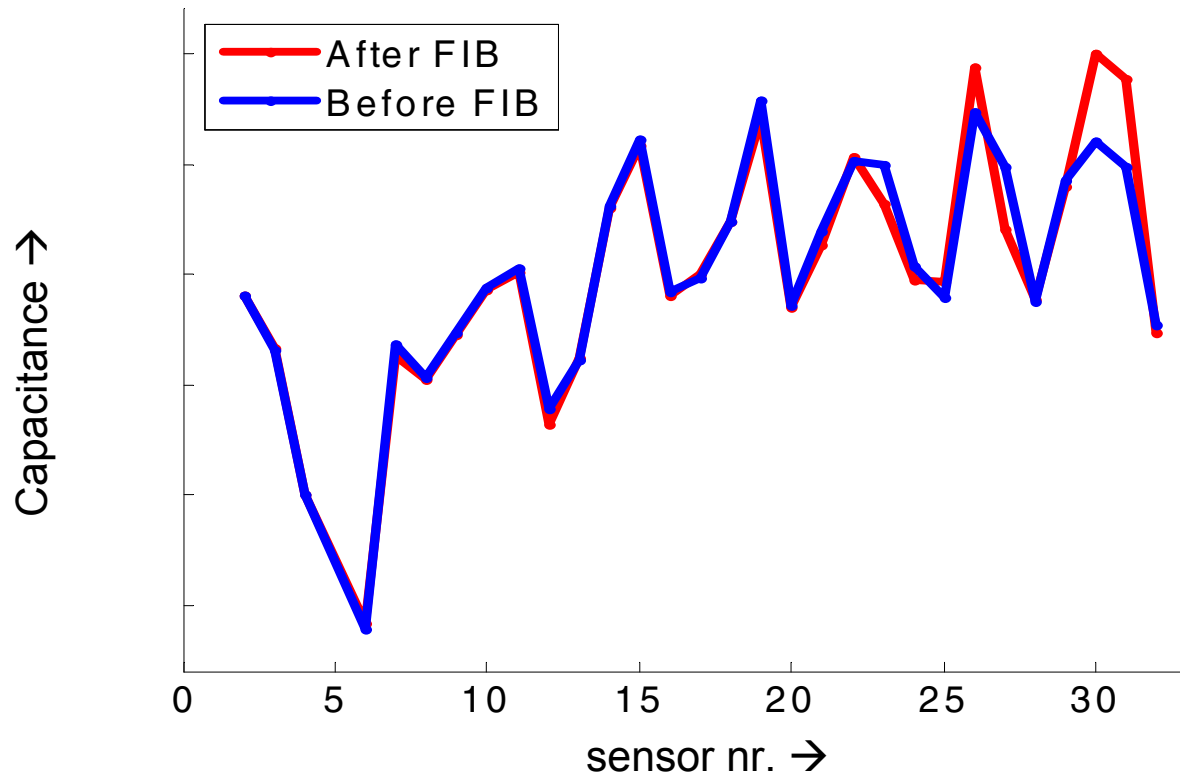**Key Extraction**

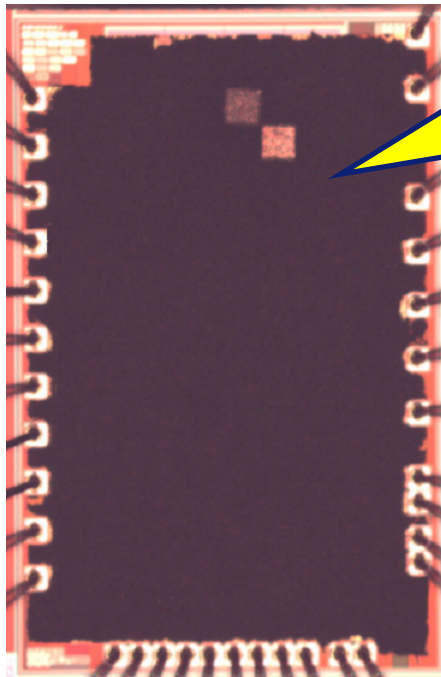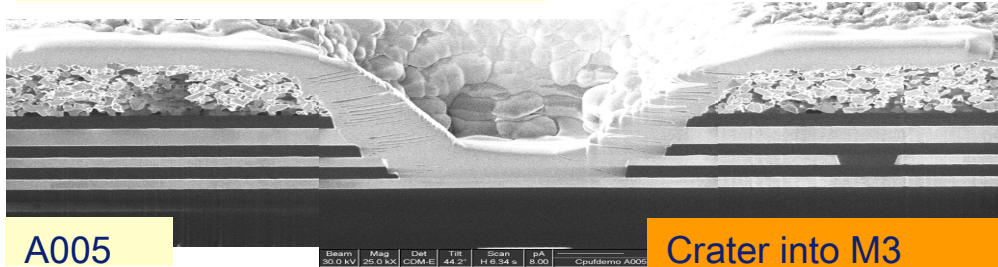# Store key temporarily in Volatile Memory

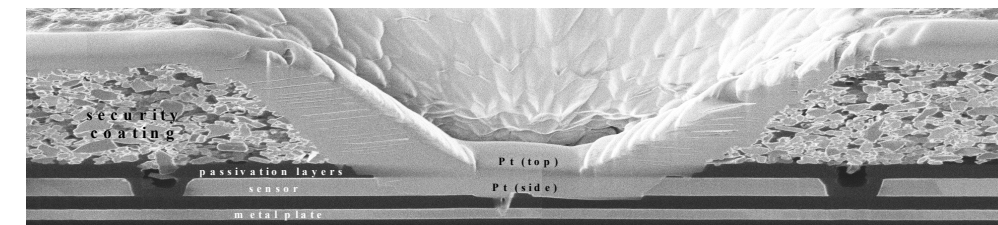# Delete key afterwards

Attack Detection

Focused Ion Beam Attack

Craters: 10 μm x10 μm

A005

Crater into M3

3.0-3.5 coating

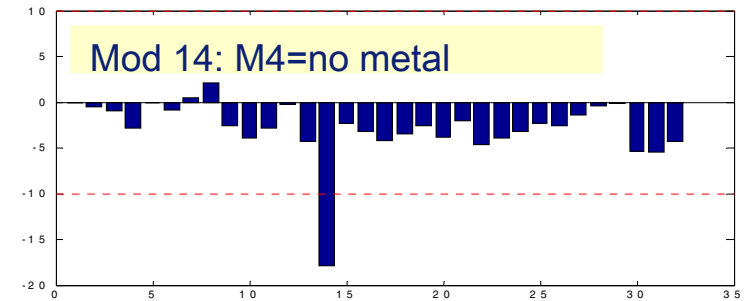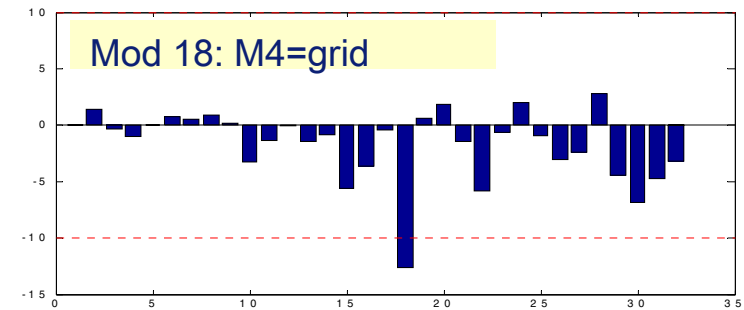Mod 18: M4=grid

A026

Crater into M3

3.0-3.5 coating

Mod 14: M4=no metal

A026

Crater into IMD4

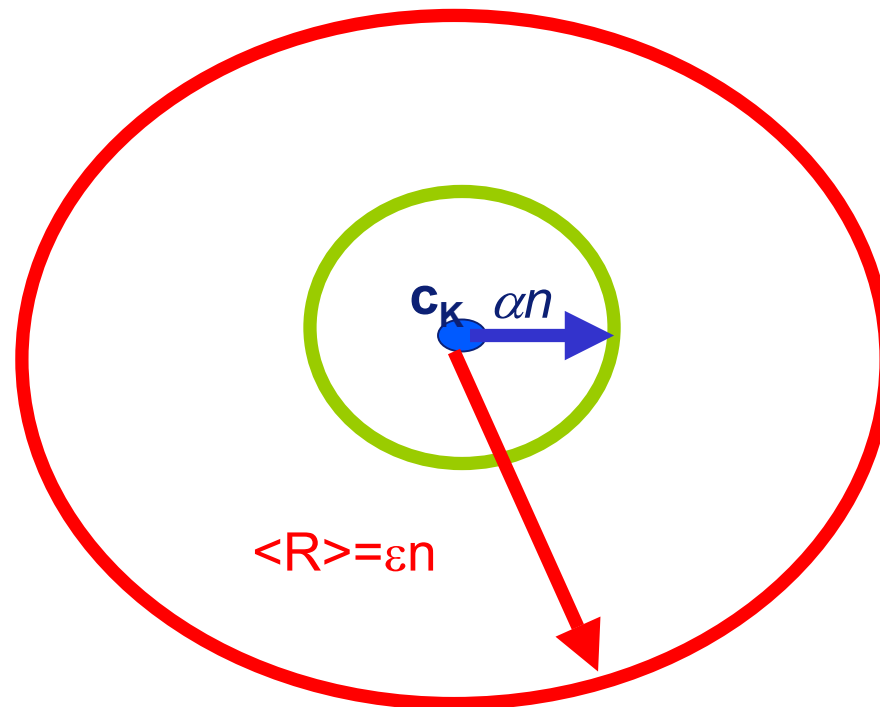6.0-6.5 coating

Mod 10: M4=plate

Next: craters of 5x5 mu

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29

Model of Key Damage

Unattacked Device: Measurement Channel: $X \to Y$　Model BSC: Error Rate: α

Attacked Device: Measurement Channel: $X \to Z$　　Model BSC: Error Rate: ε

Fuzzy Extractor corrects αn errors

$$c_K \quad \alpha n$$

$$\langle R \rangle = \varepsilon n$$

N_c = density of codewords x volume ball = $2^{n(h(\varepsilon)-h(\alpha))}$

Key Damage: Experiments

X
(Enrollment)

Y
(Reconstruction)

Z
(After FIB)

ε**=11/90**

α**=1/30**

Attack Complexity:

$N_c = 2^{51}$ **for 128 bit keys**

Summary of Results

- Test ICs with 30 sensors per IC
- Deriving 3 bits per sensor $\rightarrow$ 90 bits per IC
- Limit error correction: 4 of the 90 bits
  - Depends on the coarseness of the quantisation
- Temperature compensation
- No humidity influence

Conclusions

- Developed Read-Proof Hardware (Invasive Attacks)
  - Coating PUF
  - Fuzzy Extractor
- Made a demonstrator
  - Attacks can be detected
  - Key Damage is shown
- Next Steps
  - Further investigate side-channel leakages
  - Investigate the impact of smaller holes